

IEC QUALITY ASSESSMENT SYSTEM (IECQ) covering Electronic Components, Assemblies, Related Materials and Processes

For rules and details of the IECQ visit <u>www.iecq.org</u>

Schedule of Scope to Certificate of Approval

Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 22.0003-01

CB Certificate No.: 50600440 ITL

Schedule Number: IECQ-L ULTW 22.0003-01-S Rev No.: 2 Revision Date: 2023/04/27 Page 1 of 3

Appendix-1 (50600440 ITL) Schedule of Scope to Certificate of Approval

| Test Items | Standard/Method |
|-----------------------------------|---|
| ESD Human Body Model (HBM) | ANSI/ESDA/JEDEC JS-001-2017 |
| | AEC-Q100-002 AEC-Q101-001 |
| | MIL-STD-883 |
| ESD Machine Model (MM) | JESD22-A115 |
| | ANSI/ESDA/JEDEC JS-002-2018 |
| ESD Charged Device Model (CDM) | ARSI/13DA/JEDEC 33-002-2018 AEC-Q100-011 |
| | AEC-Q101-005 |
| | JESD78 |
| IC Latch-Up Test (LU) | AEC-Q100-004 |
| | MIL-STD-883 |
| Preconditioning Test | JESD22-A113 |
| | IPC/JEDEC J-STD-020 |
| | IPC/JEDEC J-STD-033 |
| Acoustic Microscopy for | IPC/JEDEC J-STD-035 |
| Nonhermetic Encapsulated | |
| Electronic Components | |
| High / Low Temperature Operating | JESD22-A108 |
| Teat (HTOL / LTOL) | MIL-STD-883 MIL-STD-750 |
| | |
| Temperature and Bias Life Test | AEC-Q101 AEC-Q102 |
| | JESD22-A108 |
| | MIL-STD-750 |
| | MIL-STD-883 |
| High Temperature Gate Bias (HTGB) | AEC-Q101 |
| | JESD22-A108 |

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IECQ-P Schedule of Scope Rev. 01



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| High Temperature Reverse Bias (HTRB) | AEC-Q101 JESD22-A108 |
|---|---|
| High Humidity High Temperature Reverse Bias (H ³ TRB) | AEC-Q101 JESD22-A101 |
| High Temperature Storage Life Test | JESD22-A103 |
| Low Temperature Storage Life Test | JESD22-A119 |
| Early Life Failure Rate (ELFR) | JESD74 AEC-Q100-008 JESD85 |
| Highly Accelerated Temperature and Humidity Stress Test (HAST) | JESD22-A110 |
| Accelerated Moisture Resistance - Unbiased HAST (UHAST) & Unbiased Autoclave (AC) | JESD22-A118 JESD22-A102 |
| Temperature-Humidity Biased Life Test | JESD22-A101 |
| Cycled Temperature and Humidity Biased Life Test (Moisture Resistance) | JESD22-A100 MIL-STD-883 |
| Temperature Cycling Test | JESD22-A104 MIL-STD-883 |
| Power and Temperature Cycling Test | JESD22-A105 |
| Intermittent Operational Life | MIL-STD-750 |
| Temperature Shock Test | MIL-STD-810 |
| Moisture Sensitivity Level (MSL) | JESD22-A113 IPC/JEDEC J-STD-020 IPC/JEDEC J-STD-033 |
| Thermal Stress Test | IPC/JEDEC J-STD-020 IPC-TM-650 Method 2.6.27 |

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| Moisture and Insulation Resistance | IPC-TM-650 Method 2.6.3 |
|--------------------------------------|--------------------------|
| Test and | IPC-TM-650 Method 2.6.25 |
| Conductive Anodic Filament (CAF) | |
| Resistance | |
| Program / Erase Endurance and Data | JESD22-A117 |
| Retention Stress Test (EDR) | AEC-Q100-005 |
| Dye and Pull Test (Dye and Pry Test) | IPC-TM-650 Method 2.4.53 |
| Solderability Test | IPC J-STD-002 |
| | IPC J-STD-003 |
| Conductive Resistance Test | IPC-TM-650 Method 2.5.32 |
| | IPC-9701 |
| PCB Hot Oil Test | IPC-TM-650 Method 2.4.6 |
| PCB Solder Float Resistance Test | IPC-TM-650 Method 2.4.13 |

Michael Chou Technical Reviewer of DQS:

Date: 04/27/2023

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